

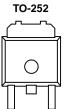
19N10V-VB Datasheet N-Channel 100 V (D-S) MOSFET

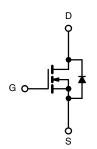
PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
	$0.055 \text{ at V}_{GS} = 10 \text{ V}$	25				
100	0.057 at $V_{GS} = 4.5 \text{ V}$	25	21nC			

FEATURES

- Trench power MOSFET
- 100 % UIS tested







APPLICATIONS

• Primary side switch

G D S Top View	G N-Channel MOSFET
ABSOLUTE MAX	IMUM RATINGS (T _A = 25 °C, u
PARAMETER	
Drain-Source Voltage	
0-1-0	

ABSOLUTE MAXIMUM RATINGS	(T _A = 25 °C, unless	otherwise note	d)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	100		
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		25		
Continuous Drain Current (T. 175 °C)	T _C = 70 °C		20		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 b, c		
	T _A = 70 °C		10 b, c		
Pulsed Drain Current		I _{DM}	75	A	
Continuous Courses Dunis Diada Coursest	T _C = 25 °C		50 e		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c		
Avalanche Current Pulse		I _{AS}	33		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	55	mJ	
	T _C = 25 °C		83		
Maximum Power Dissipation	T _C = 70 °C		58	14/	
	T _A = 25 °C	P _D	8.3 b, c	W	
	T _A = 70 °C		5.8 b, c		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +175	°C	

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R_{thJA}	15	18	°C/W		
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/VV		

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 50 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.



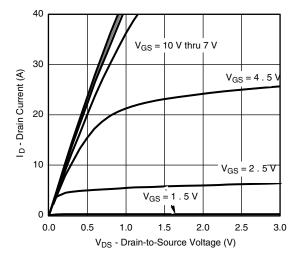
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	165	-	mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$	-	-11	-	mv/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0		3.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	Inno	V _{DS} = 100 V, V _{GS} = 0 V	-	=	1	μА	
Zero date voltage Drain Gunerit	I _{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$	-	-	10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D=12A}$	-	0.055		Ω	
Praint Course on State Medicance	$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$			0.057			
Forward Transconductance a	9fs	V _{DS} = 15 V, I _D = 12 A	-	25	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	1800	-	pF	
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	180	-		
Reverse Transfer Capacitance	C _{rss}		-	60	-		
Total Gate Charge	Q_g		-	21	32	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-		
Gate-Drain Charge	Q_{gd}		-	9	-		
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω	
Turn-On Delay Time	t _{d(on)}		-	10	15		
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$	-	10	15		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 10$ A, $V_{GEN}=10$ V, $R_g=1~\Omega$	-	15	25	ns	
Fall Time	t _f		-	10	15		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	50	_	
Pulse Diode Forward Current ^a	I _{SM}		-	-	40	A	
Body Diode Voltage	V_{SD}	I _S = 10 A	-	0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	10 A 11/11 100 A/ T 57 30	-	100	150	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$	-	38	-		
Reverse Recovery Rise Time	t _b		-	12	-	ns	

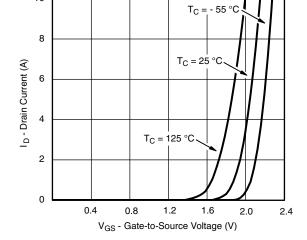
Note

- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

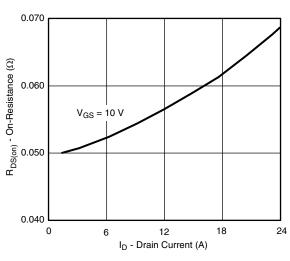


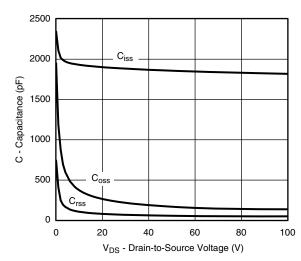




Output Characteristics

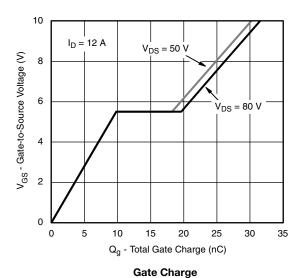
Transfer Characteristics

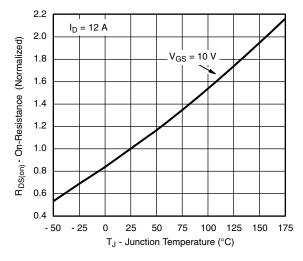




On-Resistance vs. Drain Current

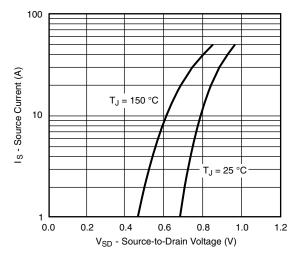
Capacitance



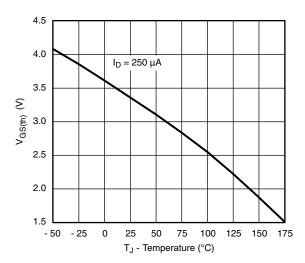


On-Resistance vs. Junction Temperature

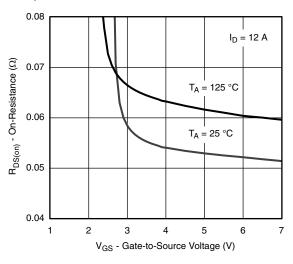




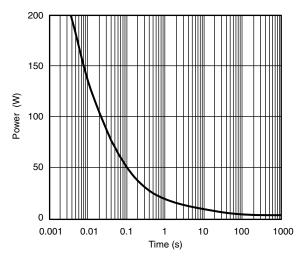
Source-Drain Diode Forward Voltage



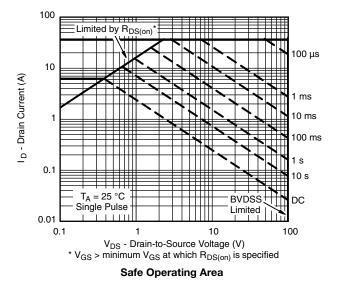
Threshold Voltage



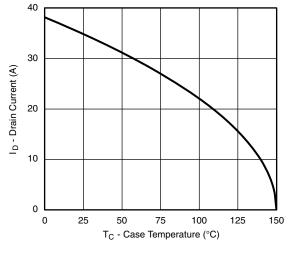
R_{DS(on)} vs. V_{GS} vs. Temperature

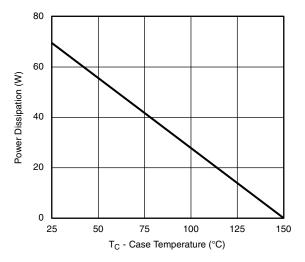


Single Pulse Power, Junction-to-Ambient









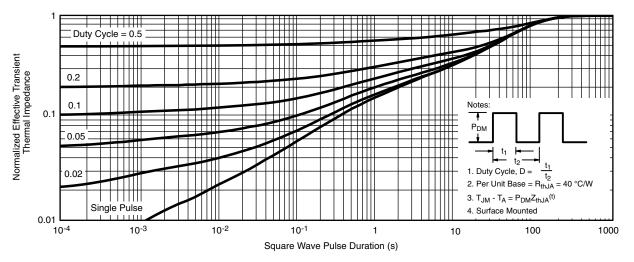
Current Derating a

Power Derating

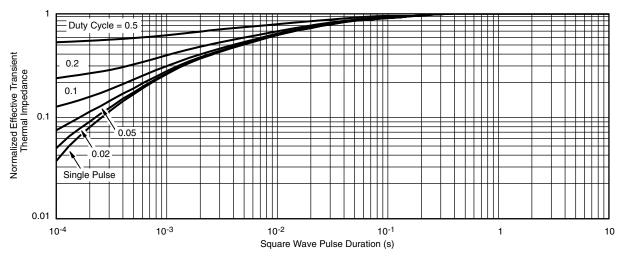
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





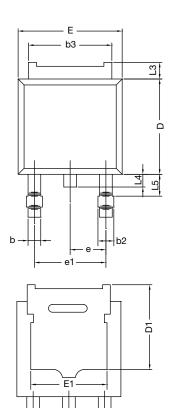
Normalized Thermal Transient Impedance, Junction-to-Ambient

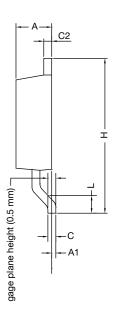


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIN	METERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	4.10	-	0.161	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	BSC	0.090	BSC		
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.01	1.52	0.040	0.060		
ECN: T16-0236-Rev. P, 16-May-16						

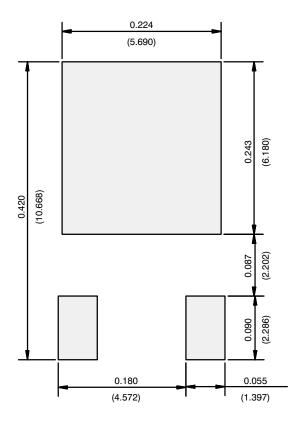
DWG: 5347

Notes

• Dimension L3 is for reference only.



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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